# Physical Properties of Volcanic Material (Tephra) Using Visible Near-Infrared Spectroscopy

and a state of the D. Marius Necsoiu (210-522-5541, mnecsoiu@swri.org), <sup>1</sup> Donald M. Hooper, <sup>2</sup> and John Roseberry <sup>1</sup> <sup>1</sup> Department of Earth, Material, and Planetary Sciences (DEMPS)<sup>2</sup> Center for Nuclear Waste Regulatory Analyses (CNWRA) Southwest Research Institute<sup>®</sup>, 6220 Culebra Road, San Antonio, TX 78238

### INTRODUCTION

Sunset Crater, Arizona, has been studied as an analog area for latent eruption and posteruption surface processes near the potential high-level waste repository at Yucca Mountain, Nevada. The evolution of basaltic tephra deposit in a semiarid climate is of particular interest and can be evaluated by studying the relationship between visible near-infrared (NIR) reflectance and physical properties of volcaniclastic (eolian) material.

Several previous studies (e.g., Leu, 1977; Johnson et al., 1992; and Okin and Painter, 2003) have investigated the relationship between reflectance spectroscopy and the grain size of unconsolidated or powdered rocks and minerals. The objective of this research is to understand the relationship between physical properties of tephra and NIR reflectance and compare these results to the expected relationship noted by previous studies.

#### **EOLIAN TEPHRA DEPOSITS**

Eolian tephra deposits were sampled because they offer the opportunity to examine basaltic volcanic material that has been reworked by surface processes and redistributed. Additionally, eolian deposits are easily sampled over a grain-size range from 0.106 to 2 mm [0.004 to 0.078 in]the desired range for spectroscopic analyses.



Coppice dunes (arrows) are composed of eolian redistributed tephra from the Sunset Crater eruption.

-1.0

0.0

0.75 1.25 1.75

2.25

2.75

3.25

## SAMPLE DATA COLLECTION AND PREPARATION

The geologic samples collected in the field were analyzed in the laboratory with the Analytical Spectral Devices FieldSpec® 3 portable spectroradiometer. Diffuse-reflectance spectra were collected from five samples with each of the samples being sieved into 8 different sieve fractions (splits). Each spectral measurement was performed without interference from specular reflectance. The setup configuration, such as the angle of incident light and the distance of light illumination and sample surface, were consistent through the measurement process. Because random noise is reduced by the square root of the number of spectra averaged, a large number of samples (e.g., 60) were averaged per measurement. In addition, several measurements were performed on different locations of the sample to obtain measurement results that are more representative of the entire sample.

Five eolian redistributed tephra samples	Sieve No.	Mesh size (Diam, inches)	Mesh size (Diam, mm)	
analysis (MN62406-5, MN62406-6,	10	0.078	2	
MN62606-13, MN62706-27, MN62906-32).	18	0.039	1	
Each sample was sieved with standard	30	0.024	0.6	
mesh sizes. Volume of fractions less than	40	0.017	0.425	
0.106 mm [0.004 in] was too small for	50	0.012	0.300	
collection of spectral data.	70	0.008	0.212	
	100	0.006	0.150	
	140	0.004	0.106	





Sieved Sample MN62906-32, Grain-size range from 0.106 mm to 2 mm. Scale bar represents 2 mm.

# CLASSIFICATION SCHEME

Grain Shape Angular, subangular, subrounded, rounded

Grain Texture by Degree of Vesicularity: Vesicularity was classified as very high when the majority of grains predominantly comprised vesicles (bubble voids) grading, through high, medium, low, and very low when there were few or no vesicles.

#### Weathered Material

The amount of weathered material (mostly postdepositional) in vesicles or on the grain surface was classified as very high when most grains were predominantly or totally coated in weathered material, grading through high, medium, low, and very low when most grains had little or no weathering.

### DATA ANALYSIS AND RESULTS

Quantitative and qualitative analyses were performed on tephra modified by eolian processes to investigate the effects of grain size, shape, texture, and weathering on spectral response. Each reflectance spectra was jump corrected at 1000 and 1800 nm (i.e., spectral discontinuities due to the spectrophotometer), and multiple measurements were averaged per sieving. Principal component analysis (PCA) was applied to decompose data by finding maximum variances so the complexity of tephra samples could be interpreted. Partial least squares was used for developing a linear calibration model between grain size (0.106 to 0.6 mm) [0.004 to 0.024 in] and spectral reflectance of sieve fractions.





#### DISCUSSIONS

The trends observed in the spectral reflectance of the analyzed fractions of tephra samples showed that an orderly relationship exists between reflectance and geometry, grain size, and mixing with nontephra grains.

In the near-infrared wavelength range, the grain size of a homogenous sample generally affects the reflectance properties such that an increase in grain size produces a decrease in reflectance (Clark, 1999). This observation seems to generally agree with our eolian samples such that an increase in grain size produces a decrease in reflectance. This trend is particularly true for grain-size sieve fractions less than 0.6 mm [0.024 in].



ANGULAR SUBANGULAR SUBROUNDED ROUNDED





particles tend to have a higher fraction of vesicles than small particles.

#### CONCLUSIONS

degree of oxidized tephra and nontephra material

erosion of tephra deposits, and grain-size characteristics.

# REFERENCES

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#### Acknowledgments

insights in data pretreatment and analysis methods.

does not necessarily reflect the view or regulatory position of the NRC



Phi Units (-log<sub>2</sub> Diam)

# V31B-0483



American Geophysical Union Fall Meeting, San Francisco, California December 10-14, 2007